



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AON3402**

**20V N-Channel MOSFET**

### General Description

The AON3402 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 1.8V while retaining a 12V  $V_{GS(MAX)}$  rating. This device is suitable for use as load switch and general purpose FET application.

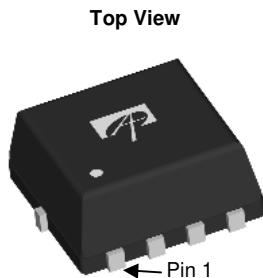
### Product Summary

$V_{DS}$  (V) = 20V  
 $I_D$  = 12.6A ( $V_{GS}$  = 4.5V)  
 $R_{DS(ON)} < 13m\Omega$  ( $V_{GS}$  = 4.5V)  
 $R_{DS(ON)} < 17m\Omega$  ( $V_{GS}$  = 2.5V)  
 $R_{DS(ON)} < 26m\Omega$  ( $V_{GS}$  = 1.8V)

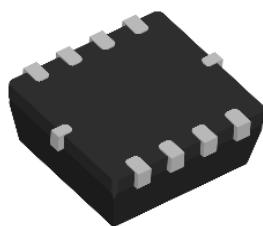
ESD Rating: 2000V HBM  
100% Rg Tested



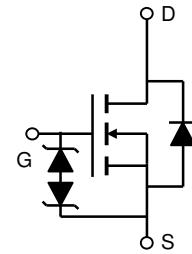
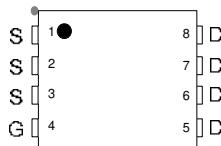
DFN 3x3



Bottom View



Top View



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current <sup>A</sup>	$I_D$	12.6	A
$T_A=70^\circ C$		10	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	40	
Power Dissipation <sup>A</sup>	$P_D$	3.1	W
$T_A=70^\circ C$		2	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	30	40	°C/W
Steady-State		65	80	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	20	25	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=16\text{V}, V_{GS}=0\text{V}$			10	$\mu\text{A}$
		$T_J=55^\circ\text{C}$			25	
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 10\text{V}$			10	$\mu\text{A}$
$\text{BV}_{\text{GSO}}$	Gate-Source Breakdown Voltage	$V_{DS}=0\text{V}, I_G=\pm 250\mu\text{A}$	$\pm 12$			V
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.5	0.78	1	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	40			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=12\text{A}$		10.3	13	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		14.4	18	
		$V_{GS}=2.5\text{V}, I_D=10.5\text{A}$		14.3	17	
		$V_{GS}=1.8\text{V}, I_D=8.5\text{A}$		21.7	26	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=12\text{A}$		37		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.73	1	V
$I_S$	Maximum Body-Diode Continuous Current				4.8	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		1810		pF
$C_{oss}$	Output Capacitance			232		pF
$C_{rss}$	Reverse Transfer Capacitance			200		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.6		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=12\text{A}$		17.9		nC
$Q_{gs}$	Gate Source Charge			1.5		nC
$Q_{gd}$	Gate Drain Charge			4.7		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=10\text{V}, R_L=1.0\Omega, R_{\text{GEN}}=3\Omega$		2.5		ns
$t_r$	Turn-On Rise Time			7.2		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			49		ns
$t_f$	Turn-Off Fall Time			10.8		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		20.2		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		8		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using 300  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

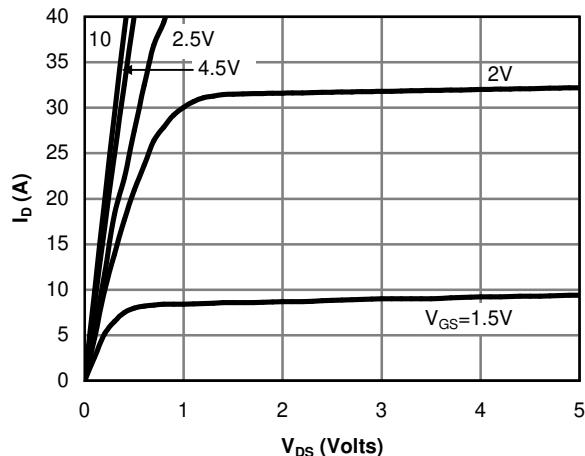


Fig 1: On-Region Characteristics

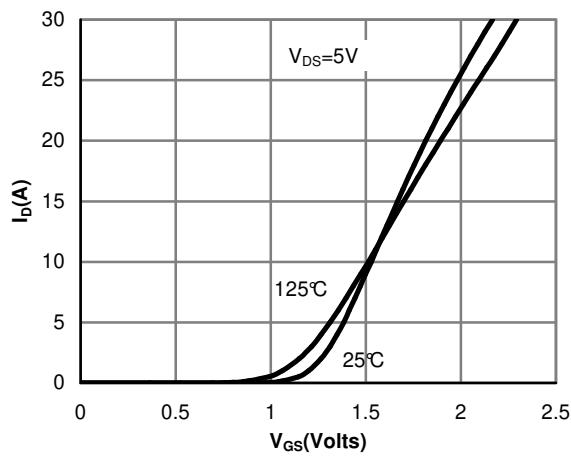


Figure 2: Transfer Characteristics

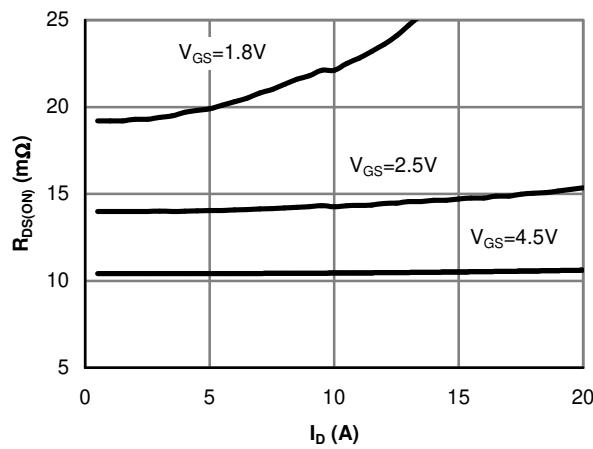


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

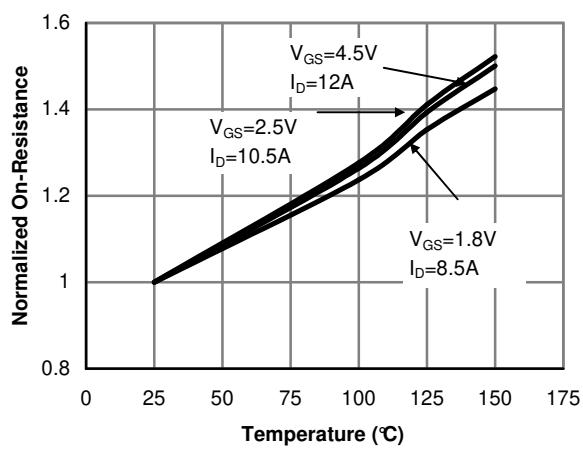


Figure 4: On-Resistance vs. Junction Temperature

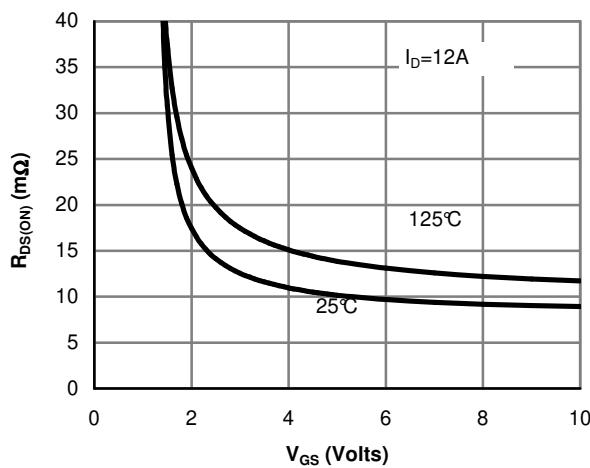


Figure 5: On-Resistance vs. Gate-Source Voltage

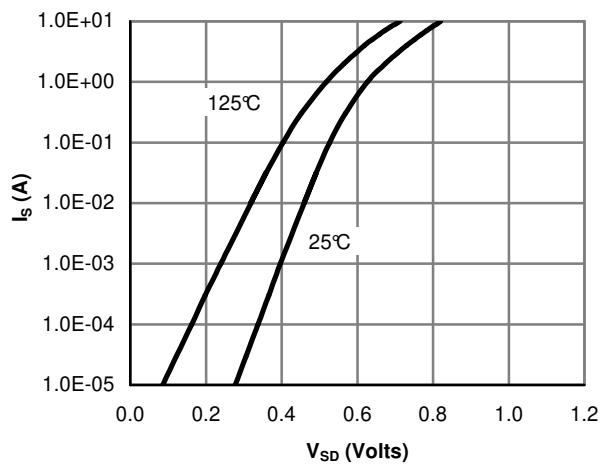


Figure 6: Body-Diode Characteristics

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